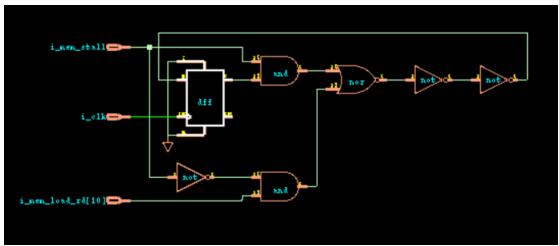
## Part A

1.A brief report describing the netlist bugs and your resolution.

There are three netlist bugs:

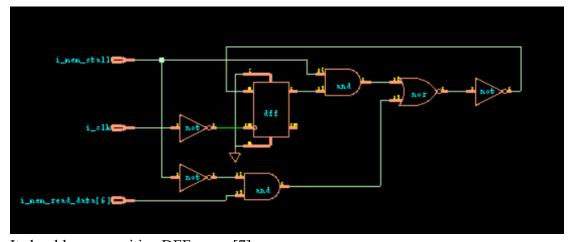
```
INVX1 U93 ( .A(n91), .Y(n880) );
The first one is INVX1 U930 (.A(n880), .Y(n88) ); causing a duplicated inverter.
```



Solution: I delete the INVX1 U930 and reconnect the wire as INVX1 U93(.A(n91),.Y(n880)),

## The second one is

```
DFFPOSX1 \mem_read_data_r_reg[7] ( .D(n53), .CLK(i_clk), .Q(
    o_wb_read_data[7]) );
DFFNEGX1 \mem_read_data_r_reg[6] ( .D(n52), .CLK(i_clk), .Q(
    o_wb_read_data[6]) );
```



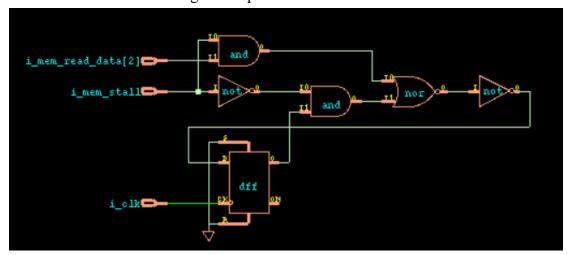
It should use a positive DFF as reg[7].

Solution: I correct the negative to positive as DFFPOSX1...

The third one is

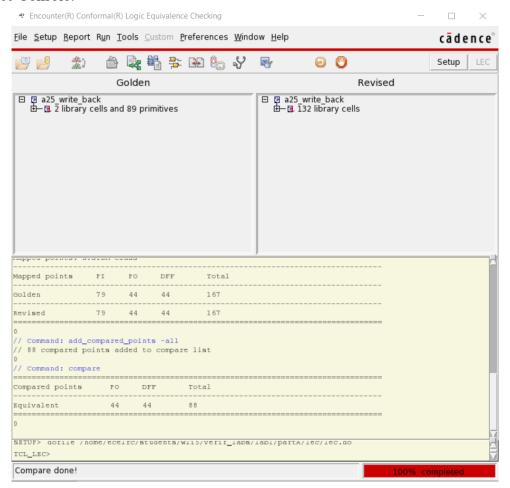
```
MUX2X1 U174 ( .B(o_wb_read_data[2]), .A(i_mem_read_data[2]), .S(i_mem_stall), .Y(n131));
INVX1 U175 ( .A(n132), .Y(n47) );
```

The MUX2x1 U174 is wrong. The input wire is reversed.

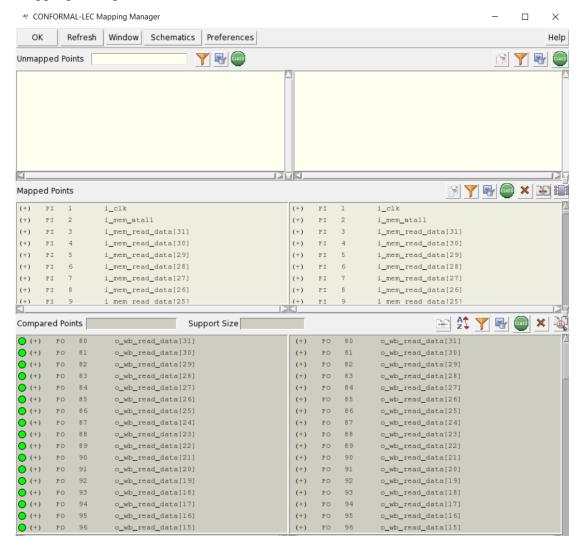


Solution: I change the order of .B and .A as MUX2X1 U174 (.B(i\_mem\_read\_data[2]), .A(o\_wb\_read\_data[2]), .S(i\_mem\_stall), .Y(n131));

#### 2.Lec Console:



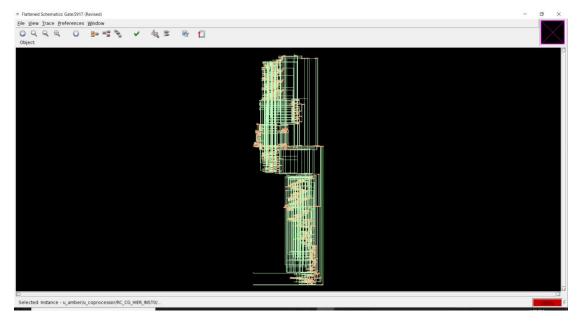
# Mapping manager:

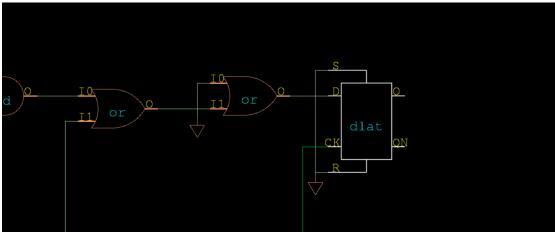


## PartB:

1. The scan style is muxed\_scan which includes scan insertion and clock gating. Since they are not present in the RTL, so I have to add constraints to disable the clock gate and the added scan logic. And in the test signal objects, since they are all in high active, I set the constraint to 0 to disable the scan.

2.





 $3.\ set\_flatten\_model \ -seq\_constant \ -seq\_constant\_x\_to \ 0$ 

Remodel registers that also have feedback to constants.

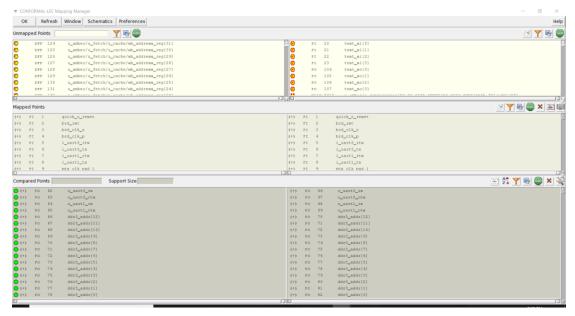
Optimize the flip-flop to a constant zero when the flop is always in a don't care (x) state. set flatten model -gated clock

Remodels the gated-clock logic of the clock port of a DFF.

set\_analyze\_option -auto

Determine the best place to run the ANALYZE SETUP command. Enable the automatic analysis.

4.mapping manager



#### Lec console

